

Search Notes



Application No.

10/047,577

Examiner

Tan Dean D. Nguyen

Applicant(s)

DAVIES ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	4/20/05	4/27/05
	7	4/20/05	2N
	8		
	9		
	10		
	11		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
I US	4/27/05	2N
Patent		
PG Pub		
II FOREIGN		
1. EPO		
2. JPO		
3. Derwent		
III NPL		
1. Ftext 1		
2. Ftext 2		
3. NText		
Reviewing		
RCE		
Parent		